Chinastandards.org

NATIONAL STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

GB/T 17169-1997

Test method for the surface quality of polished silicon wafers and epitaxial wafers by optical-reflection

硅抛光片和外延片表面质量光反射测试方法

(English Translation)

Issued on: January 2, 1997 **Implemented on: August 1, 1998**

Issued by: State Bureau of Technical Supervision

Preview: page 1 of 2 shown, full document available. Complete English PDF, instant download:
https://chinastandards.org/standards/gb-t-17169-1997

Chinastandards.org

Table of Contents

Document data

1 Document data

Sector: National standard (Recommended).

Issuing body: State Bureau of Technical Supervision.

Date of issue: 1997-01-02.

Date of implementation: 1998-08-01.

Status: obsolete, withdrawn on 2005-10-14.

Preview: page 2 of 2 shown, full document available. Complete English PDF, instant download:
https://chinastandards.org/standards/gb-t-17169-1997